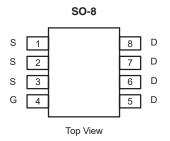


# N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (Typ.)			
40	0.014 at V <sub>GS</sub> = 10 V	10	15 nC			
70	0.016 at V <sub>GS</sub> = 4.5 V	9	13110			



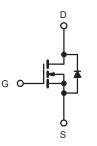
#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET<sup>®</sup> Power MOSFET
- 100 % R<sub>g</sub> Tested
- 100 % UIS Tested
- Compliant to RoHS directive 2002/95/EC



#### **APPLICATIONS**

- · Synchronous Rectification
- · POL, IBC
  - Secondary Side



N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN Parameter	Symbol	1			
Drain-Source Voltage	V <sub>DS</sub>	40	Unit		
Gate-Source Voltage	V <sub>GS</sub>	± 20	V		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	I <sub>D</sub>	10 8 10.4 <sup>a, b</sup> 8.8 <sup>a, b</sup>	Α	
Pulsed Drain Current  Avalanche Current		I <sub>DM</sub>	50 15		
Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11	mJ	
Continuous Source-Drain Diode Current $T_C = 25$ $T_A = 25$		I <sub>S</sub> —	5 2.1 <sup>a, b</sup>	Α	
Maximum Power Dissipation	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	P <sub>D</sub>	6 3.8 2.5 <sup>a, b</sup> 1.6 <sup>a, b</sup>	w	
Operating Junction and Storage Temperatur	T <sub>J</sub> , T <sub>stq</sub>	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	$R_{thJA}$	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	17	21	7 5/1		

#### Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 85 °C/W.
- d. Based on  $T_C$  = 25 °C.



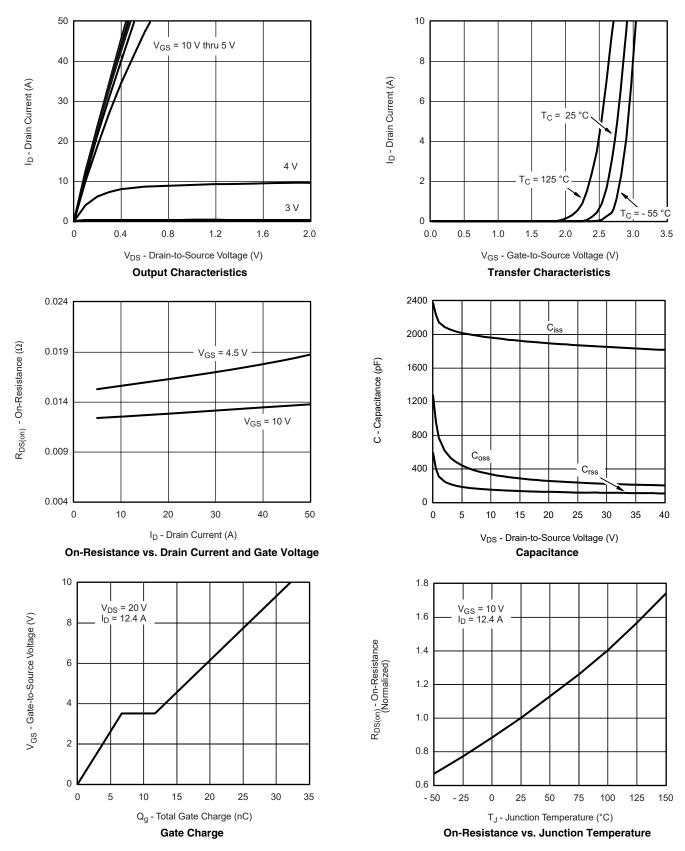
SPECIFICATIONS T <sub>J</sub> = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				1	ı		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 µA		40		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 6		11107	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1		3	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	lana	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ	
Zero Gate voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			5		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			Α	
Drain-Source On-State Resistance <sup>a</sup>	P	$V_{GS} = 10 \text{ V}, I_D = 12.4 \text{ A}$		0.014		0	
Diain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 10.8 A		0.016		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 12.4 A		56		S	
Dynamic <sup>b</sup>						•	
Input Capacitance	C <sub>iss</sub>			2000		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, f = 1 MHz		260			
Reverse Transfer Capacitance	C <sub>rss</sub>			150			
T. 1.0.1.01	_	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 12.4 A		33	50		
Total Gate Charge	Q <sub>g</sub>		15	23	1		
Gate-Source Charge	$Q_{gs}$	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 12.4 A		6.7		nC	
Gate-Drain Charge	$Q_{gd}$			5.1			
Gate Resistance	$R_{g}$	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			25	40		
Rise Time	t <sub>r</sub>	$V_{DD} = 20 \text{ V, R}_{L} = 2 \Omega$		12	20		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		25	40		
Fall Time	t <sub>f</sub>			10	15		
Turn-On Delay Time	t <sub>d(on)</sub>			10	15	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 20 \text{ V, R}_{1} = 2 \Omega$		15	25	- - -	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		30	45		
Fall Time	t <sub>f</sub>	_		10	15		
Drain-Source Body Diode Characteristi	cs			L			
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			30		
Pulse Diode Forward Current	I <sub>SM</sub>				50	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 10 A, V <sub>GS</sub> = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	-		30	60	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 10 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		26	52	nC	
Reverse Recovery Fall Time	t <sub>a</sub>			17.5			
Reverse Recovery Rise Time	t <sub>b</sub>			12.5		ns	

#### Notes

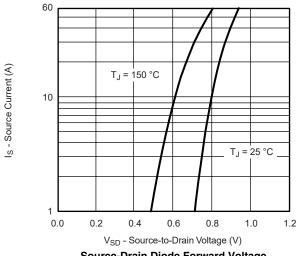
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

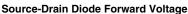
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

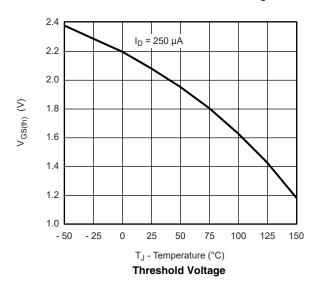






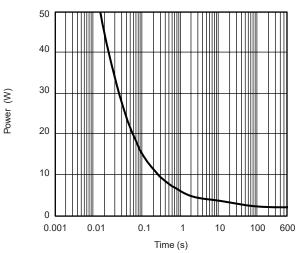




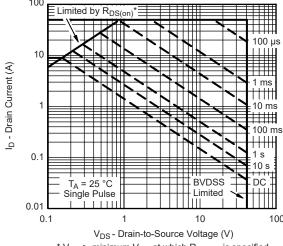


0.030 I<sub>D</sub> = 12.4 A 0.025  $R_{DS(on)}$  - On-Resistance  $(\Omega)$ 0.020 125 °C 0.015 0.010 25 °C 0.005 0.000 0 10 V<sub>GS</sub> - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



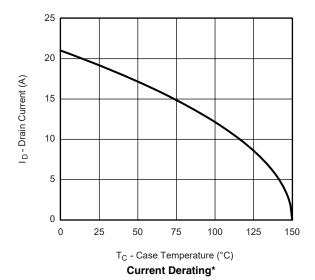
Single Pulse Power (Junction-to-Ambient)

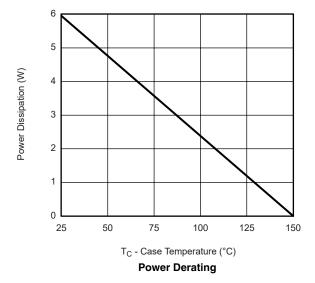


\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient

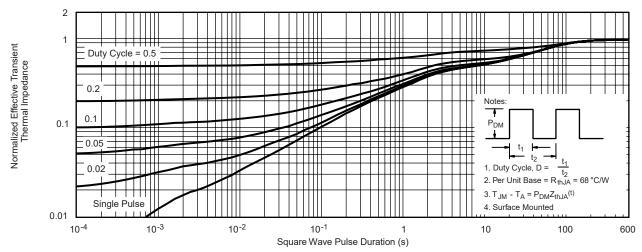




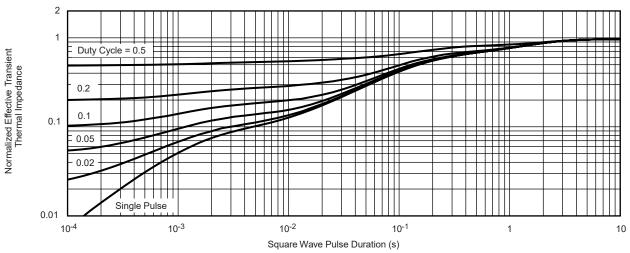


<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





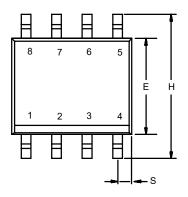
Normalized Thermal Transient Impedance, Junction-to-Ambient

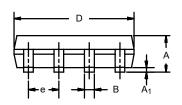


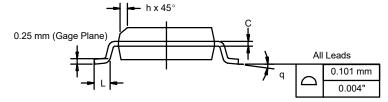
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012





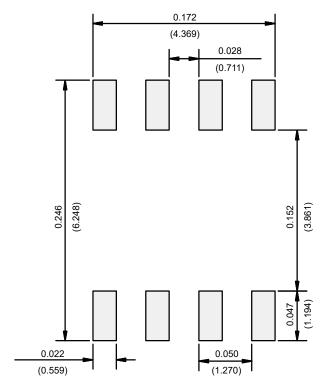


	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-0652	27-Rev. I, 11-Sep-0	6				

DWG: 5498



### **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 DMP22D4UFO-7B DMN1006UCA6-7 DMN16M9UCA6-7
STF5N65M6 IRF40H233XTMA1 STU5N65M6 DMN6022SSD-13 DMN13M9UCA6-7 DMTH10H4M6SPS-13 DMN2990UFB-7B
IPB80P04P405ATMA2 2N7002W-G MCAC30N06Y-TP MCQ7328-TP BXP7N65D BXP4N65F AOL1454G WMJ80N60C4 BXP2N20L
BXP2N65D BXT1150N10J BXT1700P06M TSM60NB380CP ROG RQ7L055BGTCR DMNH15H110SK3-13 SLF10N65ABV2
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